

Search Notes

Application/Control No.

10/626,369

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

CHENG ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
99	594,		
222	137,145.8	6/9/2005	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	6/9/2005	AW